REMARKS

Status of the Claims

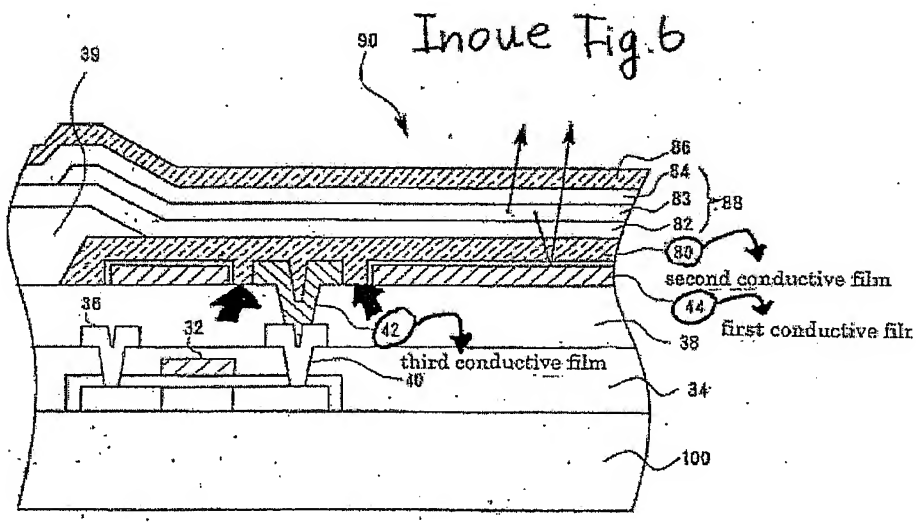
Claims 2-3, 6, 12-18 and 20-23 are pending. No new matter has been added by way of the present submission. For instance, claims 2, 18 and 23 have been amended to clarify that the third conductive film is in direct contact with each of the first conductive film and the second conductive film as supported by at least Figure 5B of the present application. Further, claims 18 and 23 now recite subject matter taken from claim 19, now cancelled. Thus, no new matter has been added.

Reconsideration of this application, as amended, is respectfully requested.

Issue Under 35 U.S.C. § 102(a)/(e)

Claims 2, 6, 12 and 14-17 stand rejected under 35 U.S.C. § 102(a) and 102(e) as being anticipated by Inoue et al., U.S. 2003/0156239 (hereinafter referred to as Inoue '239). This rejection is respectfully traversed.

The Examiner rejects claim 2 with reference to Fig. 6 of Inoue '239. Specifically, the Examiner alleges that in Fig. 6, the reference numeral 44 corresponds to the first conductive film of the present invention, the reference numeral 80 corresponds to the second conductive film of the present invention and the reference numeral 42 corresponds to the third conductive film of the present invention as recited in present claim 2. The allegations of the Examiner can be shown by using Fig. 6 of Inoue '239 as follows:

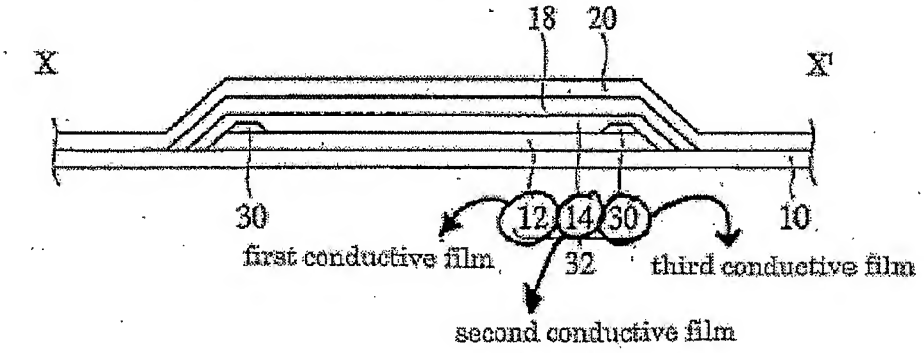


In the previous arguments, it was asserted that the above configuration does not include the feature of present claim 2 whereby "a third conductive film...is electrically connected to each of the first conductive film and the second conductive film." Accordingly, Inoue '239 does not satisfy the above feature of the present invention, and an effect whereby the electrical connection between a first conductive film and a second conductive film is improved cannot be obtained. However, the Examiner maintains the rejection alleging that the metal layer 42 is in fact electrically connected to the electrodes 44 and the transparent conductive layer 80.

In this regard, Applicant submits that claim 2 is distinct from Inoue '239 due to at least the following points.

There is a difference in configuration between the present invention and Inoue '239. Specifically, the third conductive film of the present invention is in direct contact with the first conductive film and the second conductive film as shown in Fig. 5B.

FIG. 5B Present Invention



Current claim 2 recites this feature as "a third conductive film which is partially formed between the first conductive film and the second conductive film." In order to further clarify this feature of configuration, Applicant has amended claim 2 by incorporating the feature "the third conductive film is in direct contact with each of the first conductive film and the second conductive film." In this regard, the metal layer 42 of Inoue '239 does not directly contact the electrode 44. Accordingly, Applicant believes that based on this amendment, the constitutional difference between the present invention and that of Inoue '239 should be

recognized by the Examiner.

Also, there is a difference in electrical conductivity of the first to third conductive films between the present invention and that of Inoue '239.

In a case in which an anode electrode is provided at the side of a reflective electrode of an organic EL, materials having high working function, such as ITO or IZO may be used. In this case (i.e., ITO or IZO being formed so as to cover the reflective electrode made of Al), ohmic conductivity tends to be impaired due to corrosion at the time of pattern formation. In the present invention, since the third conductive film is in direct contact with each of the first conductive film and the second conductive film, ohmic conductivity between the first conductive film and the second conductive film can be maintained.

With respect to ohmic contact, Inoue '239 describes that "a good ohmic contact can be achieved between the metal layer 42 and the source electrode 40" (please see paragraph [0054] on page 5 of Inoue '239). In Inoue '239, the metal layer 42 and the source electrode 40 are in direct contact with each other as shown in Fig. 6 and, as a result, good ohmic contact can be achieved. However, in Inoue '239, the metal layer 42 and the reflective layer 44 are not in direct contact with each other, therefore ohmic contact cannot be achieved therebetween.

Further, the organic EL according to the present invention can be configured such that the source electrode of TFT and the first conductive film (e.g., reflective electrode made of Al) are in contact with each other; therefore, the reflective area in the electrode of the top-emission type organic EL can be widely and effectively utilized. On the other hand, in Inoue '239, the source electrode 40 of TFT and the first conductive film (reflective layer 44) are not in contact with each other, therefore the reflective area cannot be wider than that of the present invention.

In view of the above, Applicant submits that there exists no anticipation based on Inoue '239. The Examiner is thus requested to withdraw this rejection.

Issue under 35 U.S.C. §103(a)

Claims 3 and 18-22 stand rejected under 35 U.S.C. § 103(a) as being unpatentable over Inoue '239.

Further, claim 13 stands rejected under 35 U.S.C. § 103(a) as being unpatentable over Inoue '239 in view of previously cited Murakami et al., U.S. 2004/0113544 (hereinafter referred to as Murakami '544).

Finally, claim 23 stands rejected under 35 U.S.C. § 103(a) as being unpatentable over previously cited Murakami, U.S. 2003/0127651 (hereinafter referred to as Murakami '651).

These rejections are respectfully traversed.

Applicant has distinguished Inoue '239 above. These distinctions apply equally herein and cannot be removed based on the secondary references. Therefore, the obviousness rejections are moot. Reconsideration and withdrawal thereof are respectfully requested.

Allowable Subject Matter

The Examiner states that claim 3 would be allowable if rewritten in independent form.

Applicant thanks the Examiner for the early indication of allowable subject matter in this application.

Conclusion

All of the stated grounds of rejection have been properly traversed, accommodated, or rendered moot. Applicant therefore respectfully requests that the Examiner reconsider all presently outstanding rejections and that they be withdrawn. It is believed that a full and complete response has been made to the outstanding Office Action, and as such, the present application is in condition for allowance.

Should there be any outstanding matters that need to be resolved in the present application, the Examiner is respectfully requested to contact Craig A. McRobbie, Registration No. 42,874 at the telephone number of the undersigned below to conduct an interview in an effort to expedite prosecution in connection with the present application.

If necessary, the Director is hereby authorized in this, concurrent, and future replies to charge any fees required during the pendency of the above-identified application or credit any overpayment to Deposit Account No. 02-2448.

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Respectfully submitted,

By #42874

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